Search Notes						

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/519,672	MATSUHASHI ET AL.	
Examiner	Art Unit	
David E. Bochna	3679	

SEARCHED			
Class	Subclass	Date	Examiner
			-
			•

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
			-
	-		

SEARCH N (INCLUDING SEARC	IOTES CH STRATEGY	
	. DATE	EXMR
Updated the previous search	6/3/2007	DB